

January 2015

# FAN3121 / FAN3122 Single 9-A High-Speed, Low-Side Gate Driver

#### **Features**

- Industry-Standard Pin-out with Enable Input
- 4.5-V to 18-V Operating Range
- 11.4 A Peak Sink at V<sub>DD</sub> = 12 V
- 9.7-A Sink / 7.1-A Source at V<sub>OUT</sub> = 6 V
- Inverting Configuration (FAN3121) and Non-Inverting Configuration (FAN3122)
- Internal Resistors Turn Driver Off If No Inputs
- 23-ns / 19-ns Typical Rise/Fall Times (10 nF Load)
- 18 ns to 23 ns Typical Propagation Delay Time
- Choice of TTL or CMOS Input Thresholds
- MillerDrive<sup>™</sup> Technology
- Available in Thermally Enhanced 3x3 mm 8-Lead MLP or 8-Lead SOIC Package (Pb-Free Finish)
- Rated from –40°C to +125°C
- Automotive Qualified to AEC-Q100 (F085 Versions)

## **Applications**

- Synchronous Rectifier Circuits
- High-Efficiency MOSFET Switching
- Switch-Mode Power Supplies
- DC-to-DC Converters
- Motor Control
- Automotive-Qualified Systems (F085 Versions)

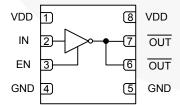


Figure 1. FAN3121 Pin Configuration

## Description

The FAN3121 and FAN3122 MOSFET drivers are designed to drive N-channel enhancement MOSFETs in low-side switching applications by providing high peak current pulses. The drivers are available with either TTL input thresholds (FAN312xT) or  $V_{\rm DD}$ -proportional CMOS input thresholds (FAN312xC). Internal circuitry provides an under-voltage lockout function by holding the output low until the supply voltage is within the operating range.

FAN312x drivers incorporate the MillerDrive™ architecture for the final output stage. This bipolar / MOSFET combination provides the highest peak current during the Miller plateau stage of the MOSFET turn-on / turn-off process.

The FAN3121 and FAN3122 drivers implement an enable function on pin 3 (EN), previously unused in the industry-standard pin-out. The pin is internally pulled up to  $V_{DD}$  for active HIGH logic and can be left open for standard operation.

The commercial FAN3121/22 is available in a 3x3 mm 8-lead thermally-enhanced MLP package or an 8-lead SOIC package. The AEC-Q100 automotive-qualified versions are available in the 8-lead SOIC package.

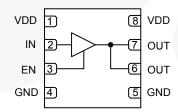


Figure 2. FAN3122 Pin Configuration

## **Ordering Information**

Part Number	Logic	Input Threshold	Package	Packing Method	Quantity per Reel
FAN3121CMPX			3x3 mm MLP-8	Tape & Reel	3,000
FAN3121CMX		CMOS	SOIC-8	Tape & Reel	2,500
FAN3121CMX_F085 <sup>(1)</sup>	Inverting		SOIC-8	Tape & Reel	2,500
FAN3121TMPX	Channels + - Enable	TTL	3x3 mm MLP-8	Tape & Reel	3,000
FAN3121TMX			SOIC-8	Tape & Reel	2,500
FAN3121TMX_F085 (1)			SOIC-8	Tape & Reel	2,500
FAN3122CMPX			3x3 mm MLP-8	Tape & Reel	3,000
FAN3122CMX	]	CMOS		Tape & Reel	2,500
FAN3122CMX_F085 <sup>(1)</sup>	Non-Inverting		SOIC-8	Tape & Reel	2,500
FAN3122TMPX	Channels + Enable		3x3 mm MLP-8	Tape & Reel	3,000
FAN3122TMX		TTL	SOIC-8	Tape & Reel	2,500
FAN3122TMX_F085 <sup>(1)</sup>			SOIC-8	Tape & Reel	2,500

For additional information on Fairchild's Eco Status, please visit: http://www.fairchildsemi.com/company/green/rohs\_green.html

#### Note:

1. Qualified to AEC-Q100.

#### **Package Outlines**



Figure 3. 3x3 mm MLP-8 (Top View)

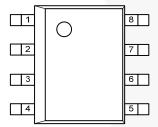


Figure 4. SOIC-8 (Top View)

### Thermal Characteristics<sup>(2)</sup>

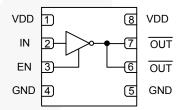
Package	Θ <sub>JL</sub> <sup>(3)</sup>	Θ <sub>JT</sub> <sup>(4)</sup>	Θ <sub>JA</sub> <sup>(5)</sup>	$\Psi_{JB}^{(6)}$	$\Psi_{JT}^{(7)}$	Units
8-Lead 3x3 mm Molded Leadless Package (MLP)	1.2	64	42	2.8	0.7	°C/W
8-Pin Small Outline Integrated Circuit (SOIC)	38	29	87	41	2.3	°C/W

#### Notes:

- Estimates derived from thermal simulation; actual values depend on the application.
- 3. Theta\_JL (Θ<sub>JL</sub>): Thermal resistance between the semiconductor junction and the bottom surface of all the leads (including any thermal pad) that are typically soldered to a PCB.
- 4. Theta\_JT (Θ<sub>JT</sub>): Thermal resistance between the semiconductor junction and the top surface of the package, assuming it is held at a uniform temperature by a top-side heatsink.
- 5. Theta\_JA (⊙<sub>JA</sub>): Thermal resistance between junction and ambient, dependent on the PCB design, heat sinking, and airflow. The value given is for natural convection with no heatsink, as specified in JEDEC standards JESD51-2, JESD51-5, and JESD51-7, as appropriate.
- 6. Psi\_JB (Ψ<sub>JB</sub>): Thermal characterization parameter providing correlation between semiconductor junction temperature and an application circuit board reference point for the thermal environment defined in Note 5. For the MLP-8 package, the board reference is defined as the PCB copper connected to the thermal pad and protruding from either end of the package. For the SOIC-8 package, the board reference is defined as the PCB copper adjacent to pin 6.
- Psi\_JT (Ψ<sub>JT</sub>): Thermal characterization parameter providing correlation between the semiconductor junction temperature and the center of the top of the package for the thermal environment defined in Note 5.

### **Pin Definitions**

	FAN3121	FAN3122	Name	Description			
	3	3	EN	<b>Enable Input</b> . Pull pin LOW to inhibit driver. EN has logic thresholds for both TTL and CMOS IN thresholds.			
	4, 5	4, 5	GND	Ground. Common ground reference for input and output circuits.			
Ī	2 2 IN		IN	nput.			
		6, 7	OUT	$\begin{tabular}{lll} \textbf{Gate Drive Output}. & \textbf{Held LOW unless required input is present and $V_{DD}$ is above the UVLO threshold.} \end{tabular}$			
	6, 7		OUT	<b>Gate Drive Output</b> (inverted from the input). Held LOW unless required input is present and $V_{\text{DD}}$ is above the UVLO threshold.			
	1, 8	1, 8	$V_{DD}$	Supply Voltage. Provides power to the IC.			
			P1	Thermal Pad (MLP only). Exposed metal on the bottom of the package; may be left floating or connected to GND; NOT suitable for carrying current.			



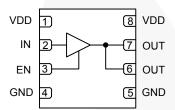


Figure 5. FAN3121 Pin Assignments (Repeated)

Figure 6. FAN3122 Pin Assignments (Repeated)

# **Output Logic**

FAN3121						
EN	IN	OUT				
0	0	0				
0	1 <sup>(8)</sup>	0				
1 <sup>(8)</sup>	0	1				
1 <sup>(8)</sup>	1 <sup>(8)</sup>	0				

FAN3122						
EN	IN	OUT				
0	0 <sup>(8)</sup>	0				
0	1	0				
1 <sup>(8)</sup>	0 <sup>(8)</sup>	0				
1 <sup>(8)</sup>	1	1				

#### Note:

8. Default input signal if no external connection is made.

# **Block Diagram**

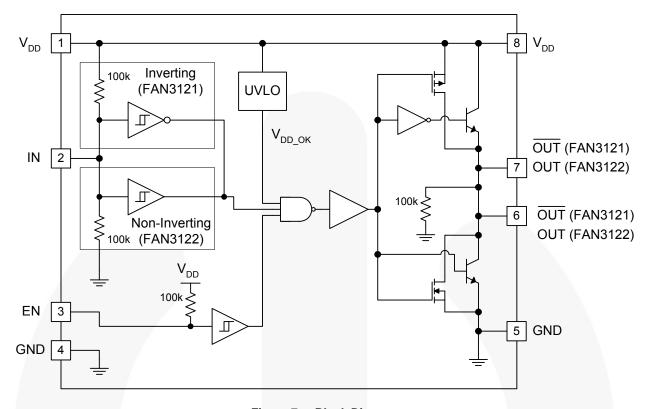


Figure 7. Block Diagram

## **Absolute Maximum Ratings**

Stresses exceeding the absolute maximum ratings may damage the device. The device may not function or be operable above the recommended operating conditions and stressing the parts to these levels is not recommended. In addition, extended exposure to stresses above the recommended operating conditions may affect device reliability. The absolute maximum ratings are stress ratings only.

Symbol	Parameter	Min.	Max.	Unit
$V_{DD}$	V <sub>DD</sub> to GND	-0.3	20.0	V
V <sub>EN</sub>	EN to GND	GND - 0.3	V <sub>DD</sub> + 0.3	V
V <sub>IN</sub>	IN to GND	GND - 0.3	V <sub>DD</sub> + 0.3	V
V <sub>OUT</sub>	OUT to GND	GND - 0.3	V <sub>DD</sub> + 0.3	V
T <sub>L</sub>	Lead Soldering Temperature (10 Seconds)		+260	°C
TJ	Junction Temperature	-55	+150	°C
T <sub>STG</sub>	Storage Temperature	-65	+150	°C

## **Recommended Operating Conditions**

The Recommended Operating Conditions table defines the conditions for actual device operation. Recommended operating conditions are specified to ensure optimal performance to the datasheet specifications. Fairchild does not recommend exceeding them or designing to Absolute Maximum Ratings.

Symbol	Parameter	Min.	Max.	Unit
$V_{DD}$	Supply Voltage Range	4.5	18.0	V
$V_{EN}$	Enable Voltage EN	0	$V_{DD}$	V
V <sub>IN</sub>	Input Voltage IN	0	$V_{DD}$	V
T <sub>A</sub>	Operating Ambient Temperature	-40	+125	°C

### **Electrical Characteristics**

Unless otherwise noted,  $V_{DD}$ =12 V and  $T_J$ =-40°C to +125°C. Currents are defined as positive into the device and negative out of the device.

Symbol	Parameter	Conditions	Min.	Тур.	Max.	Unit
Supply			•			
$V_{DD}$	Operating Range		4.5		18.0	V
	Consider Consider the Consideration of the Consider	TTL		0.65	0.90	^
$I_{DD}$	Supply Current, Inputs / EN Not Connected	CMOS <sup>(9)</sup>		0.58	0.85	− mA
V <sub>ON</sub>	Device Turn-On Voltage (UVLO)		3.5	4.0	4.3	V
V <sub>OFF</sub>	Device Turn-Off Voltage (UVLO)		3.30	3.75	4.10	V
FAN3121_	F085, FAN3122_F085 (Automotive-Qualified	Versions)			•	
$V_{DD}$	Operating Range		4.5		18.0	V
,	Supply Current Innute / EN Not Connected	TTL		0.65	1.00	m A
I <sub>DD</sub>	Supply Current, Inputs / EN Not Connected	CMOS <sup>(9)</sup>		0.58	0.85	mA
V <sub>ON</sub>	Device Turn-On Voltage (UVLO)		3.5	4.0	4.3	V
$V_{OFF}$	Device Turn-Off Voltage (UVLO) <sup>(13)</sup>		3.25	3.75	4.15	V
Inputs (TT	L, FAN312xT) <sup>(10)</sup>					•
$V_{IL_T}$	INx Logic Low Threshold		0.8	1.0		V
V <sub>IH_T</sub>	INx Logic High Threshold			1.7	2.0	V
V <sub>HYS_T</sub>	TTL Logic Hysteresis Voltage		0.40	0.70	0.85	V
FAN3121T	MX, FAN3122TMX					
I <sub>IN+</sub>	Non-Inverting Input Current	IN from 0 to V <sub>DD</sub>	-1		175	μA
I <sub>IN-</sub>	Inverting Input Current	IN from 0 to V <sub>DD</sub>	-175		1	μA
FAN3121T	MX_F085, FAN3122TMX_F085 (Automotive-	Qualified Versions)				
I <sub>INx_T</sub>	Non-inverting Input Current <sup>(13)</sup>	IN=0 V	-1.5		1.5	μA
I <sub>INx_T</sub>	Non-inverting Input Current <sup>(13)</sup>	IN=V <sub>DD</sub>	90	120	175	μA
I <sub>INx_T</sub>	Inverting Input Current <sup>(13)</sup>	IN=0 V	-175	-120	-90	μA
I <sub>INx_T</sub>	Inverting Input Current <sup>(13)</sup>	IN=V <sub>DD</sub>	-1.5		1.5	μA
Inputs (CI	MOS, FAN312xC) <sup>(10)</sup>					
V <sub>IL_C</sub>	INx Logic Low Threshold		30	38		$%V_{DD}$
V <sub>IH_C</sub>	INx Logic High Threshold			55	70	$%V_{DD}$
V <sub>HYS_C</sub>	CMOS Logic Hysteresis Voltage		12	17	24	$%V_{DD}$
FAN31210	CMX, FAN3122CMX		•	7		•
I <sub>IN+</sub>	Non-Inverting Input Current	IN from 0 to V <sub>DD</sub>	-1		175	μA
I <sub>IN-</sub>	Inverting Input Current	IN from 0 to V <sub>DD</sub>	-175		1	μA
FAN31210	CMX_F085, FAN3122CMX_F085 (Automotive	-Qualified Versions)		•		$\langle \cdot \rangle$
I <sub>INx_C</sub>	Non-Inverting Input Current <sup>(13)</sup>	IN=0 V	-1.5		1.5	μA
I <sub>INx_C</sub>	Non-Inverting Input Current <sup>(13)</sup>	IN=V <sub>DD</sub>	90	120	175	μA
I <sub>INx_C</sub>	Inverting Input Current <sup>(13)</sup>	IN=0 V	-175	-120	-90	μA
I <sub>INx_C</sub>	Inverting Input Current <sup>(13)</sup>	IN=V <sub>DD</sub>	-1.5		1.5	μA

Continued on the following page...

### **Electrical Characteristics** (Continued)

Unless otherwise noted,  $V_{DD}$ =12 V and  $T_J$ =-40°C to +125°C. Currents are defined as positive into the device and negative out of the device.

VENH         Enable           VHYS_T         TTL I           RPU         Enable           tD1, tD2         Propare           ENABLE (FAN31         VENL           VENH         Enable           VHYS_T         TTL I           RPU         Enable           tD1, tD2         Propare           tD1, tD2         Propare           Outputs         OUT           ISINK         OUT           IPK_SINK         OUT           tRISE         OUT	nle Logic Low Threshold Die Logic High Threshold Logic Hysteresis Voltage Die Pull-up Resistance agation Delay, CMOS EN <sup>(11)</sup> agation Delay, TTL EN <sup>(11)</sup> nle Logic Low Threshold Die Logic High Threshold Logic Hysteresis Voltage Die Pull-up Resistance agation Delay, CMOS EN (11) agation Threshold Logic Hysteresis Voltage Die Pull-up Resistance agation Delay, CMOS EN (11) agation Delay, TTL EN <sup>(11)</sup> Current, Mid-Voltage, Sinking (12)	EN from 5 V to 0 V EN from 0 V to 5 V	1.2 1.8 0.2 68 8 14 1.2 1.8 0.20 68 6	1.6 2.2 0.6 100 17 21 1.6 2.2 0.60 100	2.0 2.6 0.8 134 27 33 2.0 2.6 0.85	V V V V KΩ ns ns v V V V
VENH         Enable           VHYS_T         TTL I           RPU         Enable           tD1, tD2         Proparation           tD1, tD2         Proparation           ENABLE (FAN31         VENL         Enable           VENL         Enable         TTL I           RPU         Enable         Proparation           tD1, tD2         Proparation         Proparation           Outputs         ISINK         OUT           ISOURCE         OUT         OUT           IPK_SINK         OUT         OUT           IPK_SOURCE         OUT         OUT           tRISE         OUT         OUT	ble Logic High Threshold Logic Hysteresis Voltage ble Pull-up Resistance agation Delay, CMOS EN <sup>(11)</sup> agation Delay, TTL EN <sup>(11)</sup> 121_F085, FAN3122_F085) (Automotive ble Logic Low Threshold ble Logic High Threshold Logic Hysteresis Voltage ble Pull-up Resistance agation Delay, CMOS EN <sup>(11)</sup> agation Delay, TTL EN <sup>(11)</sup>	e-Qualified Versions) EN from 5 V to 0 V EN from 0 V to 5 V	1.8 0.2 68 8 14 1.2 1.8 0.20 68 6	2.2 0.6 100 17 21 1.6 2.2 0.60 100	2.6 0.8 134 27 33 2.0 2.6 0.85	V V KΩ ns ns V V
V <sub>HYS_T</sub> TTL I           R <sub>PU</sub> Enab           t <sub>D1</sub> , t <sub>D2</sub> Propa           t <sub>D1</sub> , t <sub>D2</sub> Propa           ENABLE (FAN31)         V <sub>ENL</sub> V <sub>ENL</sub> Enab           V <sub>HYS_T</sub> TTL I           R <sub>PU</sub> Enab           t <sub>D1</sub> , t <sub>D2</sub> Propa           t <sub>D1</sub> , t <sub>D2</sub> Propa           Outputs         OUT           I <sub>SINK</sub> OUT           I <sub>PK_SINK</sub> OUT           I <sub>PK_SINK</sub> OUT           t <sub>RISE</sub> Outp	Logic Hysteresis Voltage  ble Pull-up Resistance agation Delay, CMOS EN <sup>(11)</sup> agation Delay, TTL EN <sup>(11)</sup> 121_F085, FAN3122_F085) (Automotive ble Logic Low Threshold ble Logic High Threshold Logic Hysteresis Voltage ble Pull-up Resistance agation Delay, CMOS EN <sup>(11)</sup> agation Delay, TTL EN <sup>(11)</sup>	e-Qualified Versions) EN from 5 V to 0 V EN from 0 V to 5 V	0.2 68 8 14 1.2 1.8 0.20 68 6	0.6 100 17 21 1.6 2.2 0.60 100	0.8 134 27 33 2.0 2.6 0.85	V kΩ ns ns
R <sub>PU</sub>   Enable	ple Pull-up Resistance agation Delay, CMOS EN <sup>(11)</sup> agation Delay, TTL EN <sup>(11)</sup> 121_F085, FAN3122_F085) (Automotive ple Logic Low Threshold ple Logic High Threshold Logic Hysteresis Voltage ple Pull-up Resistance agation Delay, CMOS EN <sup>(11)</sup> agation Delay, TTL EN <sup>(11)</sup>	EN from 5 V to 0 V EN from 0 V to 5 V	68 8 14 1.2 1.8 0.20 68 6	100 17 21 1.6 2.2 0.60 100	134 27 33 2.0 2.6 0.85	kΩ ns ns
$\begin{array}{c cccc} t_{D1}, t_{D2} & Propate \\ t_{D1}, t_{D2} & Propate \\ \hline \textbf{ENABLE (FAN31} \\ V_{ENL} & Enable \\ V_{ENH} & Enable \\ V_{HYS\_T} & TTL & \\ R_{PU} & Enable \\ t_{D1}, t_{D2} & Propate \\ \hline \textbf{Outputs} \\ \hline \\ I_{SOURCE} & OUT \\ I_{PK\_SOURCE} & OUT \\ t_{RISE} & Output \\ \hline \end{array}$	agation Delay, CMOS EN <sup>(11)</sup> agation Delay, TTL EN <sup>(11)</sup> 121_F085, FAN3122_F085) (Automotive Delay Company Com	EN from 5 V to 0 V EN from 0 V to 5 V	1.2 1.8 0.20 68 6	17 21 1.6 2.2 0.60 100	27 33 2.0 2.6 0.85	ns ns V
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$\begin{array}{c c} \textbf{ENABLE} \ \textbf{(FAN31)} \\ \textbf{V}_{ENL} & \textbf{Enab} \\ \textbf{V}_{ENH} & \textbf{Enab} \\ \textbf{V}_{HYS\_T} & \textbf{TTL} \ \textbf{I} \\ \textbf{R}_{PU} & \textbf{Enab} \\ \textbf{t}_{D1}, \textbf{t}_{D2} & \textbf{Propa} \\ \textbf{t}_{D1}, \textbf{t}_{D2} & \textbf{Propa} \\ \textbf{Outputs} \\ \hline \\ \textbf{I}_{SINK} & \textbf{OUT} \\ \textbf{I}_{SOURCE} & \textbf{OUT} \\ \textbf{I}_{PK\_SOURCE} & \textbf{OUT} \\ \textbf{t}_{RISE} & \textbf{OUtputs} \\ \end{array}$	121_F085, FAN3122_F085) (Automotive college Logic Low Threshold college Logic High Threshold Logic Hysteresis Voltage college Pull-up Resistance agation Delay, CMOS EN (11) agation Delay, TTL EN(11)	EN from 5 V to 0 V EN from 0 V to 5 V	1.2 1.8 0.20 68 6	1.6 2.2 0.60 100	2.0 2.6 0.85	V
$\begin{array}{c cccc} V_{ENL} & Enab \\ V_{ENH} & Enab \\ V_{HYS\_T} & TTL I \\ R_{PU} & Enab \\ t_{D1}, t_{D2} & Propa \\ t_{D1}, t_{D2} & Propa \\ \hline \\ \textbf{Outputs} \\ \hline \\ I_{SINK} & OUT \\ I_{PK\_SOURCE} & OUT \\ t_{RISE} & Outputs \\ \hline \end{array}$	ole Logic Low Threshold  ole Logic High Threshold  Logic Hysteresis Voltage  ole Pull-up Resistance  agation Delay, CMOS EN (11)  agation Delay, TTL EN(11)	EN from 5 V to 0 V EN from 0 V to 5 V	1.8 0.20 68 6	2.2 0.60 100	2.6 0.85	V
$\begin{array}{c cccc} V_{ENH} & Enab \\ V_{HYS\_T} & TTL \ I \\ R_{PU} & Enab \\ t_{D1}, t_{D2} & Propa \\ t_{D1}, t_{D2} & Propa \\ \hline \\ \textbf{Outputs} \\ \hline \\ I_{SINK} & OUT \\ \hline \\ I_{PK\_SINK} & OUT \\ \hline \\ I_{PK\_SOURCE} & OUT \\ \hline \\ t_{RISE} & Outp \\ \hline \end{array}$	ble Logic High Threshold Logic Hysteresis Voltage ble Pull-up Resistance agation Delay, CMOS EN (11) agation Delay, TTL EN(11)	EN from 0 V to 5 V	1.8 0.20 68 6	2.2 0.60 100	2.6 0.85	V
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$\begin{array}{c c} R_{PU} & Enab \\ t_{D1}, t_{D2} & Propa \\ \hline t_{D1}, t_{D2} & Propa \\ \hline \textbf{Outputs} \\ \hline I_{SINK} & OUT \\ \hline I_{SOURCE} & OUT \\ \hline I_{PK\_SOURCE} & OUT \\ \hline t_{RISE} & Output \\ \hline \end{array}$	ole Pull-up Resistance agation Delay, CMOS EN (11) agation Delay, TTL EN(11)		68 6	100		V
$\begin{array}{c c} t_{D1}, t_{D2} & Propate \\ t_{D1}, t_{D2} & Propate \\ \hline \textbf{Outputs} \\ \hline I_{SINK} & OUT \\ \hline I_{SOURCE} & OUT \\ \hline I_{PK\_SOURCE} & OUT \\ \hline t_{RISE} & Outputs \\ \hline \end{array}$	agation Delay, CMOS EN (11) agation Delay, TTL EN(11)		6		4.5 :	
$\begin{array}{c c} t_{D1}, t_{D2} & Propate \\ \hline \textbf{Outputs} \\ \hline I_{SINK} & OUT \\ \hline I_{SOURCE} & OUT \\ \hline I_{PK\_SINK} & OUT \\ \hline t_{RISE} & Outp \\ \hline \end{array}$	agation Delay, TTL EN <sup>(11)</sup>			17	134	kΩ
Outputs  ISINK OUT  ISOURCE OUT  IPK_SINK OUT  IPK_SOURCE OUT  tRISE Outp			8	. ,	35	ns
I <sub>SINK</sub> OUT  I <sub>SOURCE</sub> OUT  I <sub>PK_SINK</sub> OUT  I <sub>PK_SOURCE</sub> OUT  t <sub>RISE</sub> Outp	Current, Mid-Voltage, Sinking <sup>(12)</sup>			22	34	ns
I <sub>SOURCE</sub> OUT  I <sub>PK_SINK</sub> OUT  I <sub>PK_SOURCE</sub> OUT  t <sub>RISE</sub> Outp	Current, Mid-Voltage, Sinking <sup>(12)</sup>					,
I <sub>PK_SINK</sub> OUT I <sub>PK_SOURCE</sub> OUT t <sub>RISE</sub> Outp	g-,g	OUT at V <sub>DD</sub> /2, C <sub>LOAD</sub> =1.0 μF, f=1 kHz		9.7		А
I <sub>PK_SOURCE</sub> OUT t <sub>RISE</sub> Outp	Current, Mid-Voltage, Sourcing <sup>(12)</sup>	OUT at V <sub>DD</sub> /2, C <sub>LOAD</sub> =1.0 μF, f=1 kHz		7.1		А
t <sub>RISE</sub> Outp	Current, Peak, Sinking <sup>(12)</sup>	C <sub>LOAD</sub> =1.0 µF, f=1 kHz		11.4		Α
	Current, Peak, Sourcing <sup>(12)</sup>	C <sub>LOAD</sub> =1.0 μF, f=1 kHz		10.6		Α
	out Rise Time <sup>(11)</sup>	C <sub>LOAD</sub> =10 nF	18	23	29	ns
t <sub>FALL</sub> Outp	ut Fall Time <sup>(11)</sup>	C <sub>LOAD</sub> =10 nF	11	19	27	ns
t <sub>D1,</sub> t <sub>D2</sub> Outp	ut Propagation Delay, CMOS Inputs <sup>(11)</sup>	0 – 12 V <sub>IN</sub> , 1 V/ns Slew Rate	9	18	28	ns
t <sub>D1,</sub> t <sub>D2</sub> Outp	ut Propagation Delay, TTL Inputs <sup>(11)</sup>	0 – 5 V <sub>IN</sub> , 1 V/ns Slew Rate	9	23	35	ns
I <sub>RVS</sub> Outp	ut Reverse Current Withstand <sup>(12)</sup>		1500			mA
FAN3121_F085,	FAN3122_F085 (Automotive-Qualified )	Versions)			10/1	
t <sub>RISE</sub> Outp	out Rise Time <sup>(11)</sup> CMOS Inputs	C <sub>LOAD</sub> =10 nF	12	23	31	ns
t <sub>FALL</sub> Outp	ut Fall Time <sup>(11)</sup> CMOS Inputs	C <sub>LOAD</sub> =10 nF	12	19	27	ns
	ut Rise Time <sup>(11)</sup> TTL Inputs	C <sub>LOAD</sub> =10 nF	18	23	36	ns
	ut Fall Time <sup>(11)</sup> TTL Inputs	C <sub>LOAD</sub> =10 nF	10	19	28	ns
	ut Propagation Delay, CMOS Inputs <sup>(13)</sup>	0 – 12 V <sub>IN</sub> , 1 V/ns Slew Rate	6	18	35	ns
t <sub>D1,</sub> t <sub>D2</sub> Outp	(D) (11)	0 – 5 V <sub>IN</sub> , 1 V/ns Slew Rate	9	23	36	ns
	ut Propagation Delay, TTL Inputs <sup>(11)</sup>	Voh=Vdd-Vout, lout=-1 mA		15	35	mV
V <sub>OL</sub> Low I	Level Output Voltage <sup>(13)</sup>	VOH=VDD-VOUT, IOUT=-1 MA	i	10		

#### Notes

- 9. Lower supply current due to inactive TTL circuitry.
- 10. EN inputs have modified TTL thresholds; refer to the ENABLE section.
- 11. See Timing Diagrams of Figure 8 and Figure 9.
- 12. Not tested in production.
- 13. Automotive-qualified F085 version specifications.

# **Timing Diagrams**

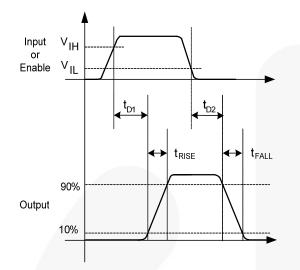


Figure 8. Non-Inverting

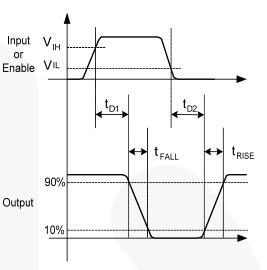


Figure 9. Inverting

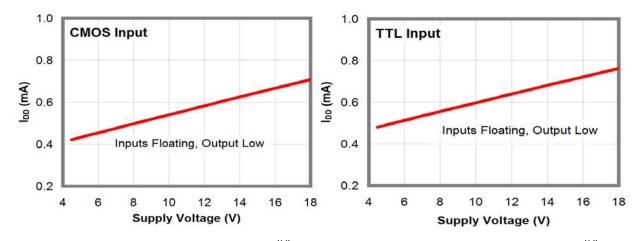


Figure 10. I<sub>DD</sub> (Static) vs. Supply Voltage<sup>(14)</sup>

Figure 11. I<sub>DD</sub> (Static) vs. Supply Voltage<sup>(14)</sup>

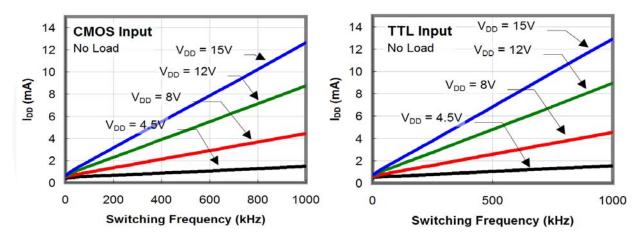


Figure 12. I<sub>DD</sub> (No-Load) vs. Frequency

Figure 13. I<sub>DD</sub> (No-Load) vs. Frequency

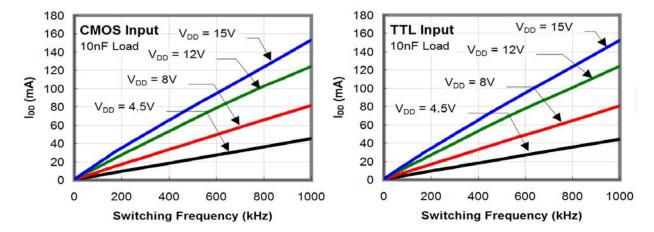


Figure 14. I<sub>DD</sub> (10 nF Load) vs. Frequency

Figure 15.  $I_{DD}$  (10 nF Load) vs. Frequency

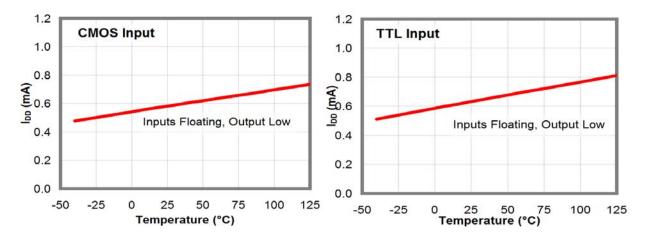


Figure 16. I<sub>DD</sub> (Static) vs. Temperature<sup>(14)</sup>

Figure 17. I<sub>DD</sub> (Static) vs. Temperature<sup>(14)</sup>

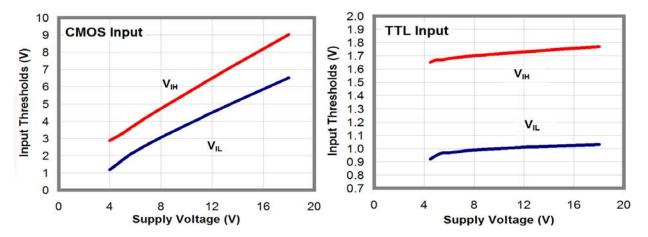


Figure 18. Input Thresholds vs. Supply Voltage

Figure 19. Input Thresholds vs. Supply Voltage

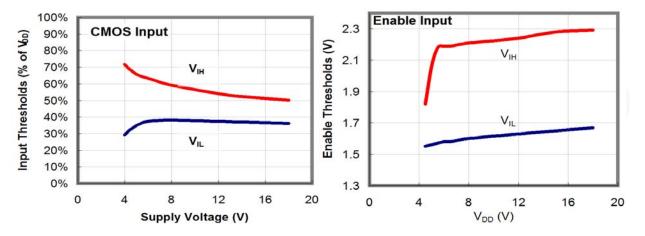


Figure 20. Input Thresholds % vs. Supply Voltage

Figure 21. Enable Thresholds vs. Supply Voltage

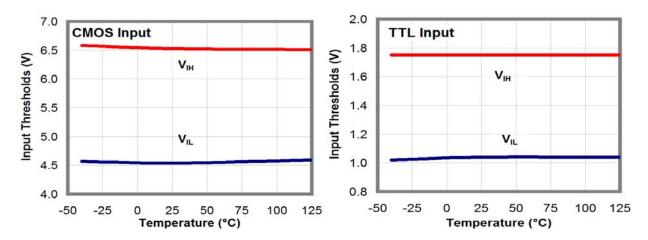


Figure 22. CMOS Input Thresholds vs. Temperature

Figure 23. TTL Input Thresholds vs. Temperature

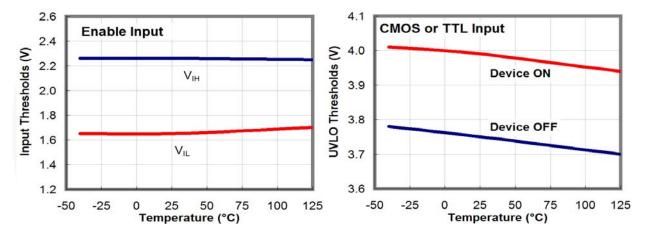


Figure 24. Enable Thresholds vs. Temperature

Figure 25. UVLO Thresholds vs. Temperature

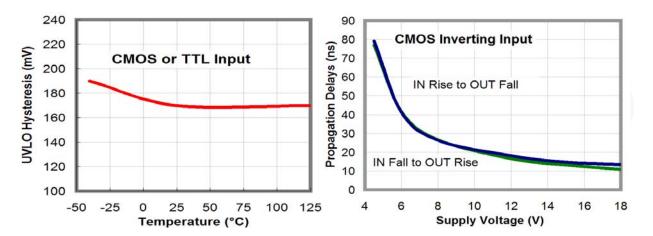


Figure 26. UVLO Hysteresis vs. Temperature

Figure 27. Propagation Delay vs. Supply Voltage

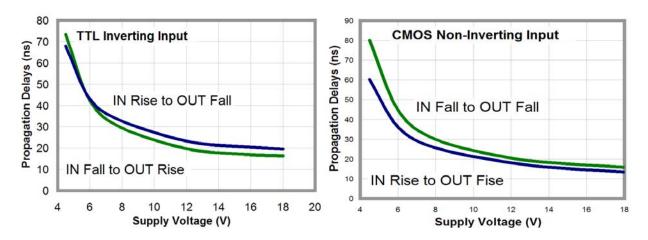


Figure 28. Propagation Delay vs. Supply Voltage

Figure 29. Propagation Delay vs. Supply Voltage

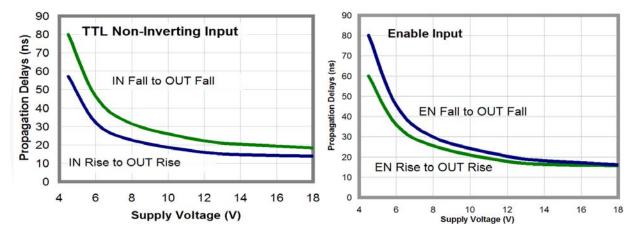


Figure 30. Propagation Delay vs. Supply Voltage

Figure 31. Propagation Delay vs. Supply Voltage

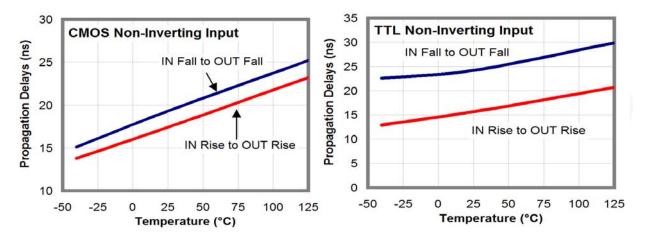


Figure 32. Propagation Delays vs. Temperature

Figure 33. Propagation Delays vs. Temperature

Typical characteristics are provided at 25°C and V<sub>DD</sub>=12 V unless otherwise noted.

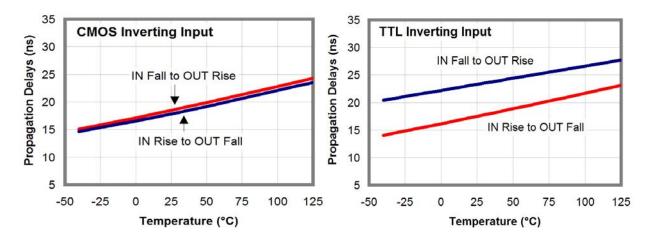


Figure 34. Propagation Delays vs. Temperature

Figure 35. Propagation Delays vs. Temperature

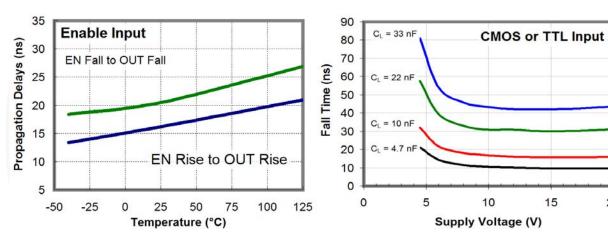


Figure 36. Propagation Delays vs. Temperature

Figure 37. Fall Time vs. Supply Voltage

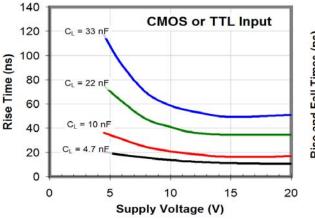


Figure 38. Rise Time vs. Supply Voltage

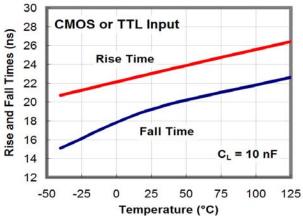
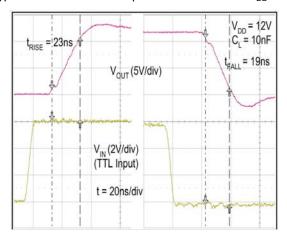


Figure 39. Rise and Fall Time vs. Temperature

20

Typical characteristics are provided at 25°C and V<sub>DD</sub>=12 V unless otherwise noted.



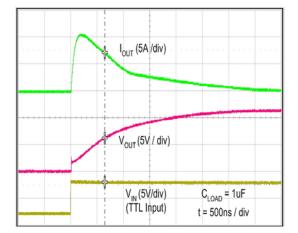
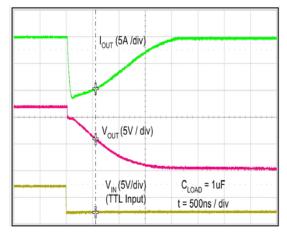


Figure 40. Rise / Fall Waveforms with 10 nF Load

Figure 41. Quasi-Static Source Current with V<sub>DD</sub>=12V<sup>(15)</sup>



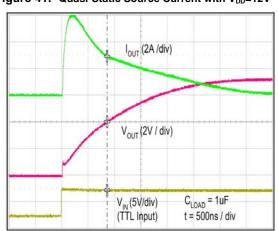
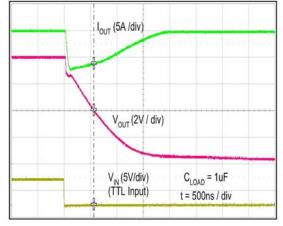


Figure 42. Quasi-Static Sink Current with V<sub>DD</sub>=12 V<sup>(15)</sup>

Figure 43. Quasi-Static Source Current with  $V_{\text{DD}}$ =8  $V^{(15)}$ 



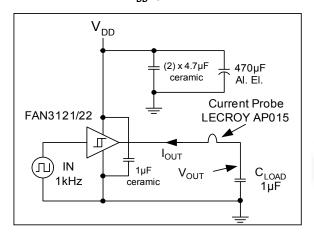


Figure 44. Quasi-Static Sink Current with V<sub>DD</sub>=8 V<sup>(15)</sup>

Figure 45. Quasi-Static I<sub>OUT</sub> / V<sub>OUT</sub> Test Circuit

#### Notes:

- 14. For any inverting inputs pulled LOW, non-inverting inputs pulled HIGH, or outputs driven HIGH; static I<sub>DD</sub> increases by the current flowing through the corresponding pull-up/down resistor, shown in Figure 7.
- 15. The initial spike in each current waveform is a measurement artifact caused by the stray inductance of the current-measurement loop.

### **Applications Information**

The FAN3121 and FAN3122 family offers versions in either TTL or CMOS input configuration. In the FAN3121T and FAN3122T, the input thresholds meet industry-standard TTL-logic thresholds independent of the  $V_{\rm DD}$  voltage, and there is a hysteresis voltage of approximately 0.7 V. These levels permit the inputs to be driven from a range of input logic signal levels for which a voltage over 2 V is considered logic HIGH. The driving signal for the TTL inputs should have fast rising and falling edges with a slew rate of 6 V/ $\mu$ s or faster, so the rise time from 0 to 3.3 V should be 550 ns or less.

The FAN3121 and FAN3122 output can be enabled or disabled using the EN pin with a very rapid response time. If EN is not externally connected, an internal pull-up resistor enables the driver by default. The EN pin has logic thresholds for parts with either TTL or CMOS IN thresholds.

In the FAN3121C and FAN3122C, the logic input thresholds are dependent on the  $V_{DD}$  level and, with  $V_{DD}$ of 12 V, the logic rising edge threshold is approximately 55% of  $V_{DD}$  and the input falling edge threshold is approximately 38% of V<sub>DD</sub>. The CMOS input configuration offers a hysteresis voltage approximately 17% of  $V_{\text{DD}}$ . The CMOS inputs can be used with relatively slow edges (approaching DC) if decoupling and bypass techniques incorporated in the system design to prevent noise from violating the input voltage hysteresis window. This allows setting precise timing intervals by fitting an R-C circuit between the controlling signal and the IN pin of the driver. The slow rising edge at the IN pin of the driver introduces a delay between the controlling signal and the OUT pin of the driver.

#### **Static Supply Current**

In the  $I_{DD}$  (static) Typical Performance Characteristics, the curves are produced with all inputs / enables floating (OUT is LOW) and indicates the lowest static  $I_{DD}$  current for the tested configuration. For other states, additional current flows through the 100  $k\Omega$  resistors on the inputs and outputs, as shown in the block diagram (see Figure 7). In these cases, the actual static  $I_{DD}$  current is the value obtained from the curves, plus this additional current

#### MillerDrive™ Gate-Drive Technology

FAN312x gate drivers incorporate the MillerDrive<sup>TM</sup> architecture shown in Figure 46. For the output stage, a combination of bipolar and MOS devices provide large currents over a wide range of supply voltage and temperature variations. The bipolar devices carry the bulk of the current as OUT swings between 1/3 to 2/3  $V_{\text{DD}}$  and the MOS devices pull the output to the HIGH or LOW rail.

The purpose of the Miller Drive™ architecture is to speed up switching by providing high current during the Miller plateau region when the gate-drain capacitance of the MOSFET is being charged or discharged as part of the turn-on / turn-off process.

For applications with zero voltage switching during the MOSFET turn-on or turn-off interval, the driver supplies high peak current for fast switching, even though the Miller plateau is not present. This situation often occurs in synchronous rectifier applications because the body diode is generally conducting before the MOSFET is switched on.

The output pin slew rate is determined by  $V_{DD}$  voltage and the load on the output. It is not user adjustable, but a series resistor can be added if a slower rise or fall time at the MOSFET gate is needed.

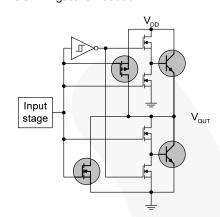


Figure 46. Miller Drive™ Output Architecture

#### **Under-Voltage Lockout (UVLO)**

The FAN312x startup logic is optimized to drive ground-referenced N-channel MOSFETs with an under-voltage lockout (UVLO) function to ensure that the IC starts in an orderly fashion. When  $V_{\rm DD}$  is rising, yet below the 4.0 V operational level, this circuit holds the output low, regardless of the status of the input pins. After the part is active, the supply voltage must drop 0.25 V before the part shuts down. This hysteresis helps prevent chatter when low  $V_{\rm DD}$  supply voltages have noise from the power switching. This configuration is not suitable for driving high-side P-channel MOSFETs because the low output voltage of the driver would turn the P-channel MOSFET on with  $V_{\rm DD}$  below 4.0 V.

#### **V<sub>DD</sub>** Bypassing and Layout Considerations

The FAN3121 and FAN3122 are available in either 8-lead SOIC or MLP packages. In either package, the  $V_{DD}$  pins 1 and 8 and the GND pins 4 and 5 should be connected together on the PCB.

In typical FAN312x gate-driver applications, high-current pulses are needed to charge and discharge the gate of a power MOSFET in time intervals of 50 ns or less. A bypass capacitor with low ESR and ESL should be connected directly between the  $V_{\text{DD}}$  and GND pins to provide these large current pulses without causing unacceptable ripple on the  $V_{\text{DD}}$  supply. To meet these requirements in a small size, a ceramic capacitor of 1  $\mu\text{F}$  or larger is typically used, with a dielectric material such as X7R, to limit the change in capacitance over the temperature and / or voltage application ranges.

Figure 47 shows the pulsed gate drive current path when the gate driver is supplying gate charge to turn the MOSFET on. The current is supplied from the local bypass capacitor  $C_{\text{BYP}}$  and flows through the driver to the MOSFET gate and to ground. To reach the high peak currents possible with the FAN312x family, the resistance and inductance in the path should be minimized. The localized  $C_{\text{BYP}}$  acts to contain the high peak current pulses within this driver-MOSFET circuit, preventing them from disturbing the sensitive analog circuitry in the PWM controller.

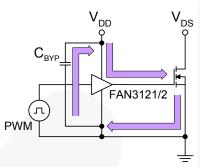


Figure 47. Current Path for MOSFET Turn-On

Figure 48 shows the path the current takes when the gate driver turns the MOSFET off. Ideally, the driver shunts the current directly to the source of the MOSFET in a small circuit loop. For fast turn-off times, the resistance and inductance in this path should be minimized.

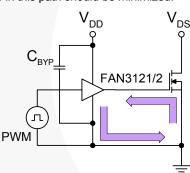


Figure 48. Current Path for MOSFET Turn-Off

#### **Operational Waveforms**

At power up, the FAN3121 inverting driver shown in Figure 49 holds the output LOW until the  $V_{DD}$  voltage reaches the UVLO turn-on threshold, as indicated in Figure 50. This facilitates proper startup control of low-side N-channel MOSFETs.

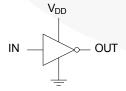


Figure 49. Inverting Configuration

The OUT pulses' magnitude follows  $V_{\text{DD}}$  magnitude with the output polarity inverted from the input until steady-state  $V_{\text{DD}}$  is reached.

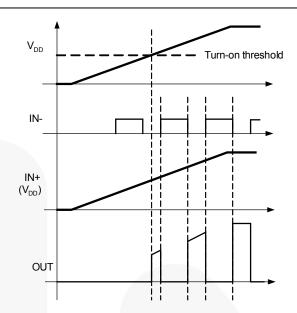


Figure 50. Inverting Startup Waveforms

At power up, the FAN3122 non-inverting driver, shown in Figure 51, holds the output LOW until the  $V_{DD}$  voltage reaches the UVLO turn-on threshold, as indicated in Figure 52. The OUT pulses magnitude follow  $V_{DD}$  magnitude until steady-state  $V_{DD}$  is reached.

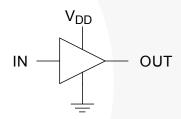


Figure 51. Non-Inverting Driver

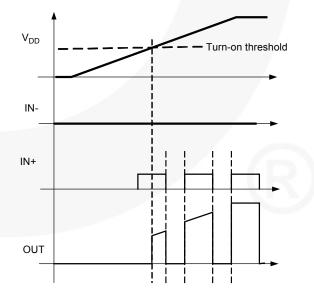


Figure 52. Non-Inverting Startup Waveforms

#### **Thermal Guidelines**

Gate drivers used to switch MOSFETs and IGBTs at high frequencies can dissipate significant amounts of power. It is important to determine the driver power dissipation and the resulting junction temperature in the application to ensure that the part is operating within acceptable temperature limits.

The total power dissipation in a gate driver is the sum of two components,  $P_{GATE}$  and  $P_{DYNAMIC}$ :

$$P_{TOTAL} = P_{GATE} + P_{DYNAMIC}$$
 (1)

Gate Driving Loss: The most significant power loss results from supplying gate current (charge per unit time) to switch the load MOSFET on and off at the switching frequency. The power dissipation that results from driving a MOSFET at a specified gate-source voltage,  $V_{\rm GS}$ , with gate charge,  $Q_{\rm G}$ , at switching frequency,  $f_{\rm SW}$ , is determined by:

$$P_{GATE} = Q_G \cdot V_{GS} \cdot f_{SW}$$
 (2)

Dynamic Pre-drive / Shoot-through Current: A power loss resulting from internal current consumption under dynamic operating conditions, including pin pull-up / pull-down resistors, can be obtained using the "IDD (No-Load) vs. Frequency" graphs in Typical Performance Characteristics to determine the current  $I_{\text{DYNAMIC}}$  drawn from  $V_{\text{DD}}$  under actual operating conditions:

$$P_{DYNAMIC} = I_{DYNAMIC} \cdot V_{DD}$$
 (3)

Once the power dissipated in the driver is determined, the driver junction rise with respect to circuit board can be evaluated using the following thermal equation, assuming  $\psi_{JB}$  was determined for a similar thermal design (heat sinking and air flow):

$$T_{J} = P_{TOTAL} \cdot \psi_{JB} + T_{B}$$
 (4)

where:

T<sub>J</sub> = driver junction temperature;

 $\psi_{\text{JB}}$  = (psi) thermal characterization parameter relating temperature rise to total power dissipation; and

T<sub>B</sub> = board temperature in location as defined in the Thermal Characteristics table.

In a full-bridge synchronous rectifier application, shown in Figure 53, each FAN3122 drives a parallel combination of two high-current MOSFETs, (such as FDMS8660S). The typical gate charge for each SR MOSFET is 70 nC with  $V_{\rm GS} = V_{\rm DD} = 9$  V. At a switching frequency of 300 kHz, the total power dissipation is:

$$P_{GATE} = 2 \cdot 70 \text{ nC} \cdot 9V \cdot 300 \text{ kHz} = 0.378 \text{ W}$$
 (5)

$$P_{DYNAMIC} = 2 \text{ mA} \cdot 9 \text{ V} = 18 \text{ mW}$$
 (6)

$$P_{TOTAL} = 0.396 \text{ W} \tag{7}$$

The SOIC-8 has a junction-to-board thermal characterization parameter of  $\psi_{JB}$  = 42°C/W. In a system application, the localized temperature around the device is a function of the layout and construction of the PCB along with airflow across the surfaces. To ensure reliable operation, the maximum junction temperature of the device must be prevented from exceeding the maximum rating of 150°C; with 80% derating,  $T_{\rm J}$  would be limited to 120°C. Rearranging Equation 4 determines the board temperature required to maintain the junction temperature below 120°C:

$$T_{B,MAX} = T_{J} - P_{TOTAL} \cdot \psi_{JB}$$
 (8)

$$T_{B,MAX} = 120^{\circ}C - 0.396 \text{ W} \cdot 42^{\circ}C/W = 104^{\circ}C$$
 (9)

For comparison, replace the SOIC-8 used in the previous example with the 3x3 mm MLP package with  $\Psi_{JB}$  = 2.8°C/W. The 3x3 mm MLP package can operate at a PCB temperature of 118°C, while maintaining the junction temperature below 120°C. This illustrates that the physically smaller MLP package with thermal pad offers a more conductive path to remove the heat from the driver. Consider tradeoffs between reducing overall circuit size with junction temperature reduction for increased reliability.

# **Typical Application Diagrams**

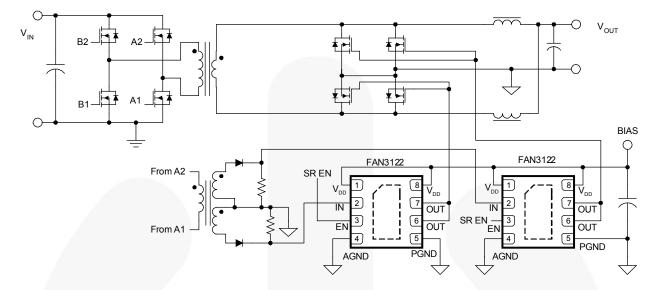


Figure 53. Full-Bridge Synchronous Rectification

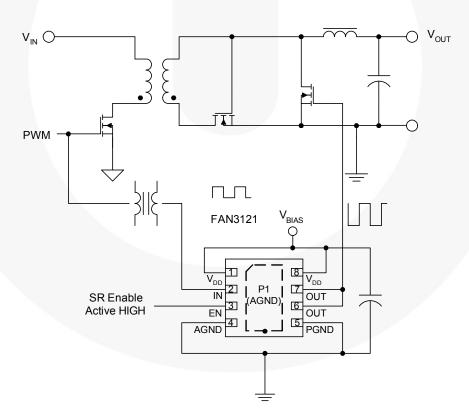


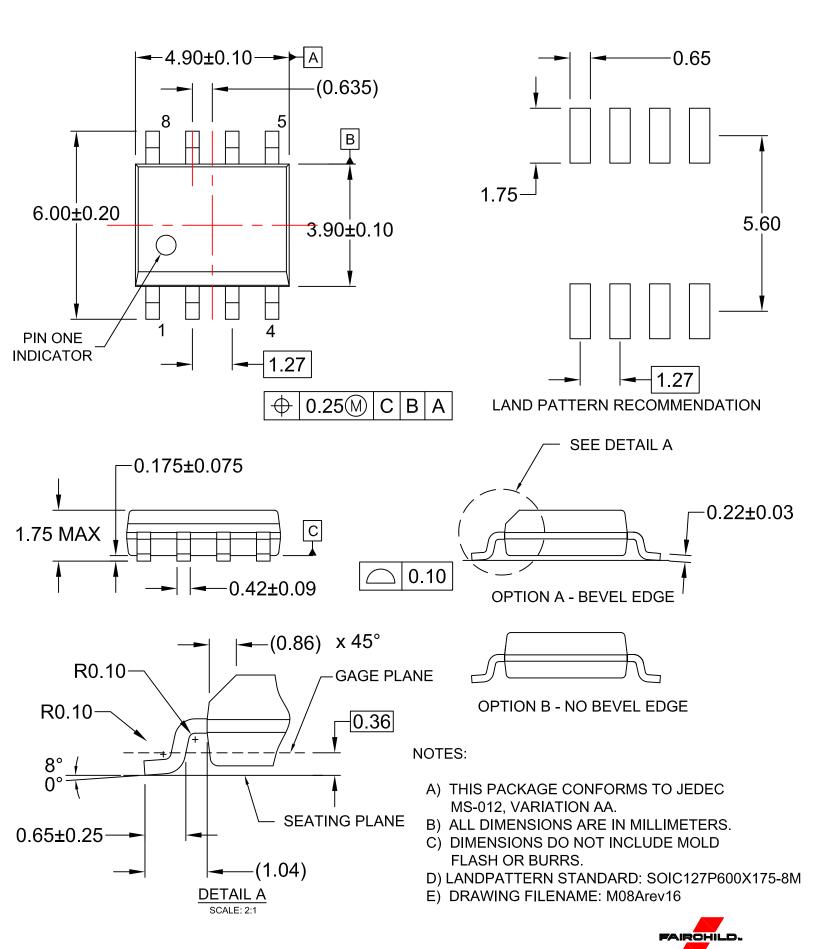
Figure 54. Hybrid Synchronous Rectification in a Forward Converter

**Table 1. Related Products** 

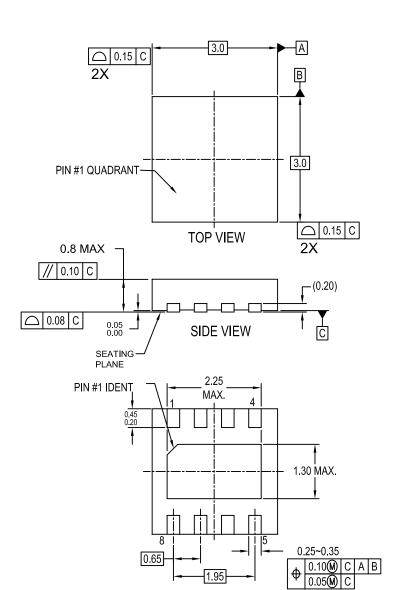
Part Number	Туре	Gate Drive <sup>(16)</sup> (Sink/Src)	Input Threshold	Logic	Package <sup>(18)</sup>
FAN3111C	Single 1 A	+1.1 A / -0.9 A	CMOS	Single Channel of Dual-Input/Single-Output	SOT23-5, MLP6
FAN3111E	Single 1 A	+1.1 A / -0.9 A	External <sup>(17)</sup>	Single Non-Inverting Channel with External Reference	SOT23-5, MLP6
FAN3100C	Single 2 A	+2.5 A / -1.8 A	CMOS	Single Channel of Two-Input/One-Output	SOT23-5, MLP6
FAN3100T	Single 2 A	+2.5 A / -1.8 A	TTL	Single Channel of Two-Input/One-Output	SOT23-5, MLP6
FAN3180	Single 2 A	+2.4 A / -1.6 A	TTL	Single Non-Inverting Channel + 3.3 V LDO	SOT23-5
FAN3216T	Dual 2 A	+2.4 A / -1.6 A	TTL	Dual Inverting Channels	SOIC8
FAN3217T	Dual 2 A	+2.4 A / -1.6 A	TTL	Dual Non-Inverting Channels	SOIC8
FAN3226C	Dual 2 A	+2.4 A / -1.6 A	CMOS	Dual Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3226T	Dual 2 A	+2.4 A / -1.6 A	TTL	Dual Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3227C	Dual 2 A	+2.4 A / -1.6 A	CMOS	Dual Non-Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3227T	Dual 2 A	+2.4 A / -1.6 A	TTL	Dual Non-Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3228C	Dual 2 A	+2.4 A / -1.6 A	CMOS	Dual Channels of Two-Input/One-Output	SOIC8, MLP8
FAN3228T	Dual 2A	+2.4 A / -1.6 A	TTL	Dual Channels of Two-Input/One-Output	SOIC8, MLP8
FAN3229C	Dual 2 A	+2.4 A / -1.6 A	CMOS	Dual Channels of Two-Input/One-Output	SOIC8, MLP8
FAN3229T	Dual 2 A	+2.4 A / -1.6 A	TTL	Dual Channels of Two-Input/One-Output	SOIC8, MLP8
FAN3268T	Dual 2 A	+2.4 A / -1.6 A	TTL	20 V Non-Inverting Channel (NMOS) and Inverting Channel (PMOS) + Dual Enables	SOIC8
FAN3278T	Dual 2 A	+2.4 A / -1.6 A	TTL	30 V Non-Inverting Channel (NMOS) and Inverting Channel (PMOS) + Dual Enables	SOIC8
FAN3223C	Dual 4 A	+4.3 A / -2.8 A	CMOS	Dual Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3213T	Dual 4 A	+4.3 A / -2.8 A	TTL	Dual Inverting Channels	SOIC8
FAN3214T	Dual 4 A	+4.3 A / -2.8 A	TTL	Dual Non-Inverting Channels	SOIC8
FAN3223T	Dual 4 A	+4.3 A / -2.8 A	TTL	Dual Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3224C	Dual 4 A	+4.3 A / -2.8 A	CMOS	Dual Non-Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3224T	Dual 4 A	+4.3 A / -2.8 A	TTL	Dual Non-Inverting Channels + Dual Enable	SOIC8, MLP8
FAN3225C	Dual 4 A	+4.3 A / -2.8 A	CMOS	Dual Channels of Two-Input/One-Output	SOIC8, MLP8
FAN3225T	Dual 4 A	+4.3 A / -2.8 A	TTL	Dual Channels of Two-Input/One-Output	SOIC8, MLP8
FAN3121C	Single 9 A	+9.7 A / -7.1 A	CMOS	Single Inverting Channel + Enable	SOIC8, MLP8
FAN3121T	Single 9 A	+9.7 A / -7.1 A	TTL	Single Inverting Channel + Enable	SOIC8, MLP8
FAN3122C	Single 9 A	+9.7 A / -7.1 A	CMOS	Single Non-Inverting Channel + Enable	SOIC8, MLP8
FAN3122T	Single 9 A	+9.7 A / -7.1 A	TTL	Single Non-Inverting Channel + Enable	SOIC8, MLP8
FAN3240	Dual 12 A	> +12.0 A	TTL	Dual-Coil Relay Driver, Timing Config. 0	SOIC8
FAN3241	Dual 12 A	> +12.0 A	TTL	Dual-Coil Relay Driver, Timing Config. 1	SOIC8

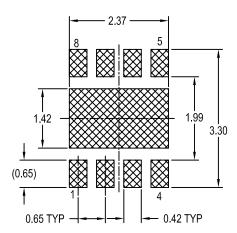
#### Notes:

- 16. Typical currents with OUT at 6 V and V<sub>DD</sub> = 12 V.
  17. Thresholds proportional to an externally supplied reference voltage.
  18. Automotive-qualified F085 versions are only offered in SOIC8 packages.



	REVISIONS							
LTR	DESCRIPTION	EDCN	DATE	BY/APP'D				
Α	RELEASE TO DOCUMENT CONTROL	MASS ECN UPDATE	10/4/2006	H.ALLEN				
	1.0mm original dim. covered both Carsem of 1.0mm max and Pg at 0.8mm max.							
2	Carsem has been dropped as a subcon for the package and		09/02/2007	H.ALLEN				
	customers want a drawing reflecting the actual max of 0.8mm							





RECOMMENDED LAND PATTERN

NOTES:

**BOTTOM VIEW** 

1.95

- A. CONFORMS TO JEDEC REGISTRATION MO-229, VARIATION VEEC, DATED 11/2001
- B. DIMENSIONS ARE IN MILLIMETERS.
- C. DIMENSIONS AND TOLERANCES PER ASME Y14.5M, 1994
- D. FILENAME: MKT-MLP08Drev2

APPROVALS	DATE	FAIR	8				
h.allen	09-02-07				epas, FIZ, Penang, Malays	ia.	
DFTG. CHK.							
ENGR. CHK.	8LD,MLP DUAL,JEDEC MO-229,						
J Chan	26-02-07	,					
			3MM SQUARE				
PROJECTIO	N	SCALE	SIZE	DRAWING NUMBER			REV
			N/A	MKT-	MLP08D		2
INCH [MM]			SCALE I	DRAWING	SHEET <sup>*</sup>	<b>1</b> of	1





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QS<sup>™</sup>
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SuperSOT™-8
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Definition of Terms		
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